



FCC 47 CFR § 2.1091

RF EVALUATION REPORT (MPE)

FOR

GSM/WCDMA/LTE/5G NR Phone + BT/BLE, DTS/UNII a/b/g/n/ac/ax, NFC,WPT and UWB

MODEL NUMBER: SC-55D, SCG22

FCC ID: A3LSMF946JPN

REPORT NUMBER: 4790841160-S3V1

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Prepared for
SAMSUNG ELECTRONICS CO., LTD.
129 SAMSUNG-RO, YEONGTONG-GU, SUWON-SI,
GYEONGGI-DO, 16677, KOREA

Prepared by

UL Korea, Ltd.

26th floor, 152, Teheran-ro, Gangnam-gu Seoul, 06236, Korea

Suwon Test Site: UL Korea, Ltd. Suwon Laboratory
218 Maeyeong-ro, Yeongtong-gu,
Suwon-si, Gyeonggi-do, 16675, Korea
TEL: (031) 337-9902
FAX: (031) 213-5433



Testing Laboratory

TL-637

Revision History

Rev.	Date	Revisions	Revised By
V1	7/6/2023	Initial Issue	--

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1. Attestation of SAR Characterization

Applicant Name	SAMSUNG ELECTRONICS CO.,LTD.
FCC ID	A3LSMF946JPN
Model Number	SC-55D, SCG22
Applicable Standards	FCC 47 CFR § 2.1091 KDB 680106 D01 RF Exposure Wireless Charging Apps
Date Tested	7/5/2023 to 7/6/2023
Test Results	Pass

UL Korea, Ltd. tested the above equipment in accordance with the requirements set forth in the above standards. All indications of Pass/Fail in this report are opinions expressed by UL Korea, Ltd. based on interpretations and/or observations of test results. Measurement Uncertainties were not taken into account and are published for informational purposes only. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.

Note: The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. This document may not be altered or revised in any way unless done so by UL Korea, Ltd. and all revisions are duly noted in the revisions section. Any alteration of this document not carried out by UL Korea, Ltd. will constitute fraud and shall nullify the document. This report must not be used by the client to claim product certification, approval, or endorsement by IAS, any agency of the Federal Government, or any agency of any government

Approved & Released By: 	Prepared By: 
Justin Park Operations Leader UL Korea, Ltd. Suwon Laboratory	Sunghoon Kim Senior Laboratory Engineer UL Korea, Ltd. Suwon Laboratory

2. Test Methodology

All calculations were made in accordance with FCC OET Bulletin 65 Edition 97-01.

3. Facilities and Accreditation

The test sites and measurement facilities used to collect data are located at 218 Maeyeong-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16675, Korea. Line conducted emissions are measured only at the 218 address. The following table identifies which facilities were utilized for radiated emission measurements documented in this report. Specific facilities are also identified in the test results sections.

218 Maeyeong-ro
<input checked="" type="checkbox"/> Shield Room 1

UL Korea, Ltd. is accredited by IAS, Laboratory Code TL-637. The full scope of accreditation can be viewed at <https://www.iasonline.org/wp-content/uploads/2017/05/TL-637-cert-New.pdf>.

4. Equipment Under Test

4.1. Description of EUT

The EUT has WPT (Wireless Power Transfer) feature which has inductive charging coil to charge phone or watch. The charging frequency is between 110 kHz to 148 kHz, and the maximum power consumption is 9.0 W in charging status.

4.2. Worst-case configuration

Folder Closed configuration

Test configuration	Description
DUT to Phone test configuration 1	Charging from Phone to DUT
DUT to Phone test configuration 2	Charging from Phone to DUT (TA Charging from DUT)
DUT to Phone test configuration 3 (Cross position)	Charging from Phone to DUT
DUT to Phone test configuration 4 (Cross position)	Charging from Phone to DUT (TA Charging from DUT)
DUT to Watch test configuration 5	Charging from Watch to DUT
DUT to Watch test configuration 6	Charging from Watch to DUT (TA Charging from DUT)

Note:

Configuration 2, 4 and 6 were tested with the worst case of configuration 1, 3 and 5.

Folder Opened configuration

Test configuration	Description
DUT to Phone test configuration 7	Charging from Phone to DUT
DUT to Phone test configuration 8	Charging from Phone to DUT (TA Charging from DUT)
DUT to Phone test configuration 9 (Cross position)	Charging from Phone to DUT
DUT to Phone test configuration 10 (Cross position)	Charging from Phone to DUT (TA Charging from DUT)
DUT to Watch test configuration 11	Charging from Watch to DUT
DUT to Watch test configuration 12	Charging from Watch to DUT (TA Charging from DUT)

Note:

Configuration 8, 10 and 12 were tested with the worst case of configuration 7, 9 and 11.

4.3. KDB 680106 D01 SECTION 5.b) EQUIPMENT APPROVAL CONSIDERATIONS

Requirement	Device informations
(1) Power transfer frequency is less than 1 MHz.	Yes. Operating Frequency is between 110kHz to 148 kHz.
(2) Output power from each primary coil is less than or equal to 15 watts.	Yes. Maximum power is 9.0 Watts.
(3) The transfer system includes only single primary and secondary coils. This includes charging systems that may have multiple primary coils and clients that are able to detect and allow coupling only between individual pairs of coils.	Yes.
(4) Client device is placed directly in contact with the transmitter.	Yes.
(5) Mobile exposure conditions only (portable exposure conditions are not covered by this exclusion).	Yes.
(6) The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.	Yes. The aggregate field at 15 cm or 20cm from the device are 12.21 % of the FCC H field limit.

4.4. Description of Test setup

SUPPORT EQUIPMENT & PERIPHERALS

SUPPROT EQUIPMENT & PERIPHERALS LIST				
Description	Manufacturer	Model	Serial Numver	FCC ID
Phone	Samsung Electronics Co., Ltd.	SM-G986B/DS	R3CMB0C70XN	A3LSMG986B
Watch	Samsung Electronics Co., Ltd.	SM-R835F	RFAM90ZXFTF	A3LSMR835
Traver Adapter	Samsung Electronics Co., Ltd.	EP-TA800	R37N9BV0382HM3	DoC
USB Data Cable	Samsung Electronics Co., Ltd.	EP-DN980BBE	N/A	-

TEST SETUP

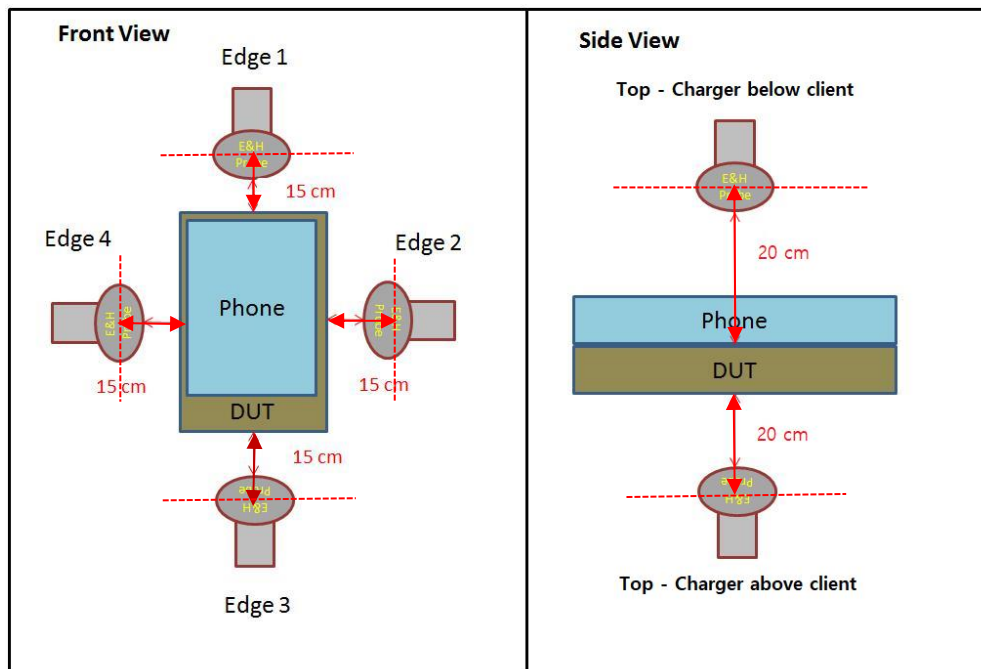
The following three modes are tested in test configurations

Mode
Operating (SUPPORT Equipment, <10% Power Charging)
Operating (SUPPORT Equipment, 50~55% Power Charging)
Operating (SUPPORT Equipment, 90~95% Power Charging)

MEASUREMENT TEST SETUP

The measurement was taken using a probe placed 15 cm surrounding the device and 20 cm above the top surface of the EUT. Measurements were taken the top (charger below/above client) and all sides of the EUT per KDB680106 D01.

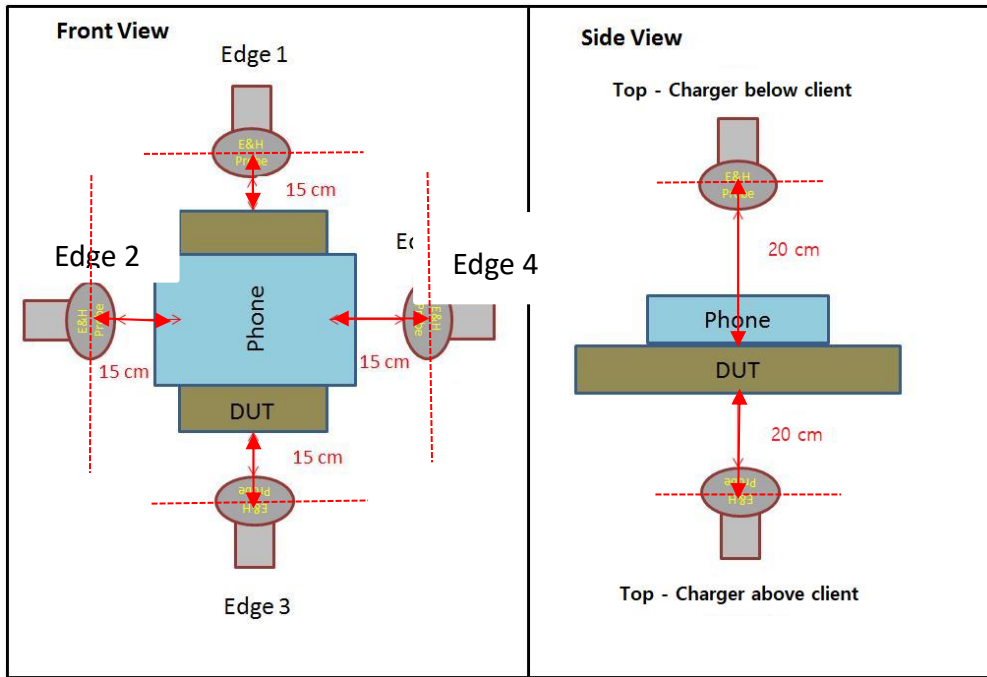
DUT to phone test Configuration 1 & 2 & 7 & 8



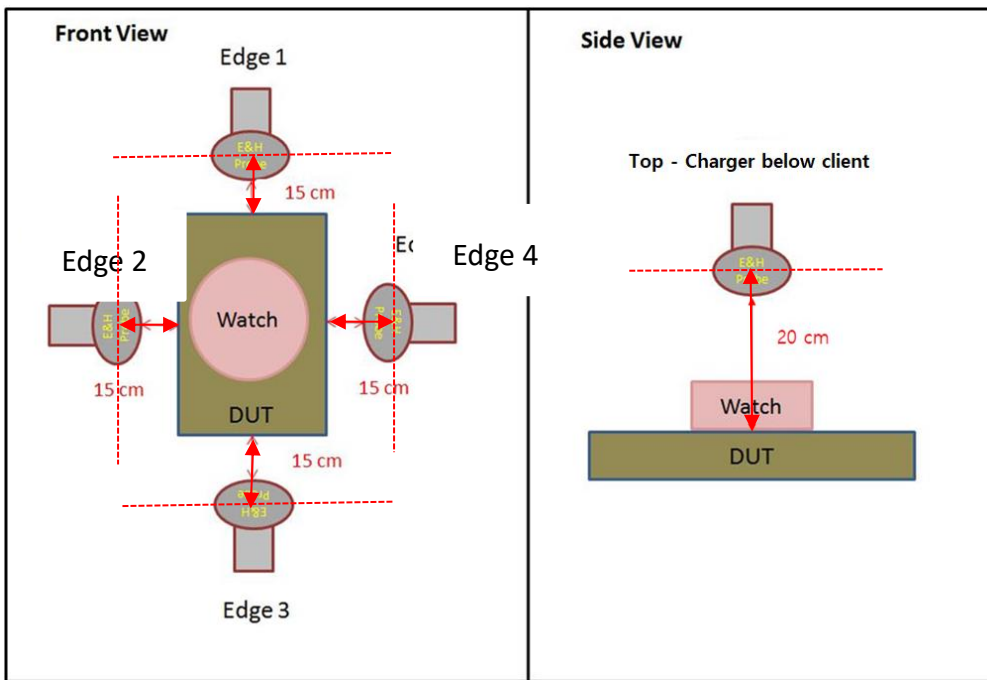
Note:

Test distance is the distance between DUT's surface to center of probe.

DUT to phone test Configuration 3 & 4 & 9 & 10



DUT to Watch test Configuration 5 & 6 & 11 & 12



Note:

Test distance is the distance between DUT's surface to center of probe.

5. Test and Measurement equipment

The following test and measurement equipment was used for the tests documented in this report;

Test equipment (Measurement probe)				
Description	Manufacturer	Model	S/N	Cal due.
E-H Field Analyzer	Narda	EHP-200AC	170WX91008	8-23-2023

6. Maximum Permissible RF exposure

6.1. FCC Limits and Summary

6.1.1. FCC Limits

§ 1.1310 The criteria listed in Table 1 shall be used to evaluate the environmental impact of human exposure to radio-frequency (RF) radiation as specified in § 1.1307(b), except in the case of portable devices which shall be evaluated according to the provisions of § 2.1093 of this chapter.

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
(A) Limits for Occupational/Controlled Exposures				
0.3–3.0	614	1.63	*(100)	6
3.0–30	1842/f	4.89/f	*(900/f ²)	6
30–300	61.4	0.163	1.0	6
300–1500	f/300	6
1500–100,000	5	6
(B) Limits for General Population/Uncontrolled Exposure				
0.3–1.34	614	1.63	*(100)	30
1.34–30	824/f	2.19/f	*(180/f ²)	30

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)—Continued

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
30–300	27.5	0.073	0.2	30
300–1500	f/1500	30
1500–100,000	1.0	30

f = frequency in MHz

* = Plane-wave equivalent power density

NOTE 1 TO TABLE 1: Occupational/controlled limits apply in situations in which persons are exposed as a consequence of their employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure. Limits for occupational/controlled exposure also apply in situations when an individual is transient through a location where occupational/controlled limits apply provided he or she is made aware of the potential for exposure.

NOTE 2 TO TABLE 1: General population/uncontrolled exposures apply in situations in which the general public may be exposed, or in which persons that are exposed as a consequence of their employment may not be fully aware of the potential for exposure or can not exercise control over their exposure.

6.2. Test Results

6.2.1. FCC RF Exposure

H-FIELD MEASUREMENTS

Note: Peak measurement were performed. Additional test was performed in each Test mode by moving the probe surrounding the device to find the maximum exposure.

TEST results of DUT(Folder Closed) to phone test Configuration 1 & 2

FCC RF Exposure Result

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas. data (A/m)			
Configuration 1	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger above client	1.63	0.029			
			Top - charger below client		0.029			
			Edge 1		0.029			
			Edge 2		0.034			
			Edge 3		0.064			
			Edge 4		0.034			
			Max		0.064			
	Operating Real Product (Power 50~55% charging)		Top - charger above client		0.029			
			Top - charger below client		0.030			
			Edge 1		0.034			
			Edge 2		0.032			
			Edge 3		0.059			
			Edge 4		0.034			
			Max		0.059			
	Operating Real Product (Power 90~95% charging)		Top - charger above client		0.039			
			Top - charger below client		0.031			
			Edge 1		0.030			
			Edge 2		0.030			
			Edge 3		0.062			
			Edge 4		0.034			
			Max		0.062			
	Configuration 2		Operating Real Product (Power <10% charging)			Edge 3		<u>0.071</u>

TEST results of DUT(Folder Closed) to phone test Configuration 3 & 4

FCC RF Exposure Result

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas. data (A/m)
Configuration 3	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger above client	1.63	0.048
			Top - charger below client		0.098
			Edge 1		0.039
			Edge 2		0.038
			Edge 3		0.047
			Edge 4		0.117
			Max		0.117
	Operating Real Product (Power 50~55% charging)		Top - charger above client		0.046
			Top - charger below client		0.088
			Edge 1		0.041
			Edge 2		0.039
			Edge 3		0.048
			Edge 4		0.118
			Max		0.118
	Operating Real Product (Power 90~95% charging)		Top - charger above client		0.044
			Top - charger below client		0.087
			Edge 1		0.043
			Edge 2		0.042
			Edge 3		0.048
			Edge 4		0.116
			Max		0.116
Configuration 4	Operating Real Product (Power 50~55% charging)		Edge 4		<u>0.121</u>

TEST results of DUT(Folder Closed) to phone test Configuration 5 & 6

FCC RF Exposure Result

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas. data (A/m)			
Configuration 5	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger below client	1.63	0.069			
			Edge 1		0.114			
			Edge 2		0.076			
			Edge 3		0.137			
			Edge 4		0.049			
			Max		0.137			
	Operating Real Product (Power 50~55% charging)		Top - charger below client		0.074			
			Edge 1		0.138			
			Edge 2		0.082			
			Edge 3		0.178			
			Edge 4		0.058			
			Max		0.178			
	Operating Real Product (Power 90~95% charging)		Top - charger below client		0.066			
			Edge 1		0.108			
			Edge 2		0.088			
			Edge 3		0.140			
			Edge 4		0.049			
			Max		0.140			
	Configuration 6		Operating Real Product (Power 50~55% charging)			Edge 3		0.153

TEST results of DUT(Folder Opened) to phone test Configuration 7 & 8

FCC RF Exposure Result

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas. data (A/m)
Configuration 7	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger above client	1.63	0.029
			Top - charger below client		0.029
			Edge 1		0.029
			Edge 2		0.029
			Edge 3		0.051
			Edge 4		0.031
			Max		0.051
	Operating Real Product (Power 50~55% charging)		Top - charger above client		0.031
			Top - charger below client		0.029
			Edge 1		0.029
			Edge 2		0.031
			Edge 3		0.056
			Edge 4		0.031
			Max		0.056
	Operating Real Product (Power 90~95% charging)		Top - charger above client		0.030
			Top - charger below client		0.031
			Edge 1		0.029
			Edge 2		0.031
			Edge 3		0.053
			Edge 4		0.033
			Max		0.053
Configuration 8	Operating Real Product (Power 50~55% charging)		Edge 3		<u>0.061</u>

TEST results of DUT(Folder Opened) to phone test Configuration 9 & 10

FCC RF Exposure Result

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas. data (A/m)
Configuration 9	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger above client	1.63	0.051
			Top - charger below client		0.084
			Edge 1		0.087
			Edge 2		0.082
			Edge 3		0.098
			Edge 4		0.110
			Max		0.110
	Operating Real Product (Power 50~55% charging)		Top - charger above client		0.052
			Top - charger below client		0.079
			Edge 1		0.083
			Edge 2		0.078
			Edge 3		0.088
			Edge 4		0.114
			Max		0.114
	Operating Real Product (Power 90~95% charging)		Top - charger above client		0.053
			Top - charger below client		0.082
			Edge 1		0.079
			Edge 2		0.081
			Edge 3		0.085
			Edge 4		0.116
			Max		0.116
Configuration 10	Operating Real Product (Power 90~95% charging)		Edge 4		0.105

TEST results of DUT(Folder Opened) to phone test Configuration 11 & 12

FCC RF Exposure Result

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas. data (A/m)			
Configuration 11	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger below client	1.63	0.077			
			Edge 1		0.095			
			Edge 2		0.035			
			Edge 3		0.183			
			Edge 4		0.097			
			Max		0.183			
	Operating Real Product (Power 50~55% charging)		Top - charger below client		0.068			
			Edge 1		0.082			
			Edge 2		0.031			
			Edge 3		0.181			
			Edge 4		0.073			
			Max		0.181			
	Operating Real Product (Power 90~95% charging)		Top - charger below client		0.077			
			Edge 1		0.096			
			Edge 2		0.038			
			Edge 3		0.199			
			Edge 4		0.093			
			Max		0.199			
	Configuration 12		Operating Real Product (Power 90~95% charging)			Edge 3		0.175

6.2.2. FCC SUMMARY OF RESULTS

H-Field Limit		
FCC RF Exposure	Maximum meas data (A/m)	Percentage (%)
1.63	0.199	12.21

Conclusion:

H-Field result is less than 50% of the MPE limit.

Appendixes

Refer to separated files for the following appendixes.

4790841160-S3 FCC Report MPE_App A_Test setup photos

END OF REPORT